

12/11/03

Sheet 1 of 5

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2463		PRIORITY SERIAL NO. 02/005,333	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT John T. Moore et al.		10/734419	
				PRIORITY FILING DATE November 26, 2001			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MEW	AA	5,219,788	6/93	Abernathy et al.			
	AB	5,045,847	9/91	Tarui et al.			
	AC	5,045,345	9/91	Singer			
	AD	4,996,081	2/91	Elul et al.			
	AE	3,884,698	5/75	Kakihama et al.			
	AF	5,518,946	5/96	Kuroda			
	AG	5,489,542	2/96	Iwai et al.			
	AH	4,330,569	5/82	Gullett et al.			
	AI	4,499,656	2/85	Fabian et al.			
	AJ	5,554,418	9/96	Ito et al.			
	AK	5,926,739	7/99	Rolfson et al.			

FOREIGN PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
MEW	AL	401086562	3/89	Japan			
	AM	362137854	6/87	Japan			
	AN	2129217	5/84	Great Britain			
	AO	2170649	8/86	Great Britain			
	AP	2145243	3/85	Great Britain			
	AQ	403075158	3/91	Japan			

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
MEW	AR	Silicon Proc. for VLSI; 177-178; Vol. 1; S. Wolf	
MEW	AS	Silicon Proc. for VLSI; 191-193; Vol. 1; S. Wolf	

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2463		PRIORITY SERIAL NO. 09/995,343	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT John T. Moore et al.		10/734419	
				PRIORITY FILING DATE November 26, 2001			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
Mew	AA	4,874,716	10/89	Rao	1	1	
	AB	5,587,344	12/96	Ishikawa			
	AC	4,439,270	3/84	Powell et al.			
	AD	5,773,325	6/98	Teramoto			
	AE	5,904,523	5/99	Feldman et al.			
	AF	5,891,793	4/99	Gardner et al.			
	AG	5,795,821	8/98	Bacchetta et al.			
	AH	5,918,147	6/99	Filipiak et al.			
	AI	5,882,978	3/99	Srinivasan et al.			
	AJ	4,612,629	9/86	Harari			
↓	AK	5,831,321	11/98	Nageyama			

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AL							
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AO							
AP							
AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
Mew	AR		Silicon Proc. for VLSI; 37-38; 598-599; Vol. 2; S. Wolf
Mew	AS		Electronic Materials Science: For Integrated Circuits; 1990 ©; Mayer et al; pp. 269-274; Pub. 1990

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT John T. Moore et al.		10/734419	
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
NEW	AA	3,549,411	12/70	Bean			
	AB	4,446,194	5/84	Candelaria			
	AC	4,485,553	12/84	Christian			
	AD	4,543,707	10/85	Ito et al.			
	AE	5,098,865	3/92	Machado et al.			
	AF	5,160,998	11/92	Itoh et al.			
	AG	5,306,946	4/94	Yamamoto			
	AH	5,442,223	8/95	Fujii			
	AI	5,523,616	6/96	Den			
	AJ	5,756,404	5/98	Friedenreich et al.			
	AK	5,834,374	11/98	Cabral Jr. et al.			
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
NEW	AR	Intrinsic Stress in Silicon Nitride and Silicon Dioxide Films Prepared by Various Deposition Techniques; 1988 IEEE Internat. Sympos. On Electrical Insulation, Boston, MA; June 5-8, 1988; 1 page; Kanicki, J. et al.					
NEW	AS	Passivation of GaAsFET's with PECVD Silicon Nitride Films of Different Stress States; IEEE Transactions on Electron Devices; Vol. 35, No. 9; Sept. 1988; pp. 1412-1418					
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2463	PRIORITY SERIAL NO. 09/006,392
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT John T. Moore et al.	
				PRIORITY FILING DATE November 26, 2001	
				PRIORITY GROUP 2815	

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MEW	AA	4,695,872	9/87	Chatterjee			
	AB	5,178,016	1/93	Dauenhauer et al.			
	AC	5,985,771	11/99	Moore et al.			
	AD	3,649,884	3/72	Haneta			
	AE	4,868,632	9/89	Hayashi			
	AF	5,304,829	4/94	Mori et al.			
	AG	5,925,494	7/99	Horn			
	AH	4,075,367	2/78	Gullett			
	AI	4,732,858	3/88	Brewer et al.			
	AJ	6,300,253	10/01	Moore, John T.			
V	AK	4,698,787	10/87	Mukherjee et al.			

FOREIGN PATENT DOCUMENTS							
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AP							
AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
MEW	AR	Silicon Nitride Overcoats for Thin Film Magnetic Recording Media; IEEE Transactions on Magnetics; Vol 27. No. 6, Nov. 1991; pp. 5070-5072	
	AS		

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2463		PRIORITY SERIAL NO. 093995392 101734419	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT John T. Moore et al.		PRIORITY GROUP 2815	
				PRIORITY FILING DATE November 26, 2001			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
NEW	AA	4,939,559	07/90	DiMaria et al.			
	AB	6,140,181	10/00	Forbes et al.			
	AC	6,143,627	11/00	Robinson			
	AD	5,877,069	03/99	Robinson			
	AE	6,093,956	07/00	Moore et al.			
	AF	6,103,619	08/00	Lai			
	AG	6,265,241	07/01	Pan			
	AH	6,420,777		Lam et al.			
	AI	6,417,559	07/02	Moore et al.			
	AJ	5,041,888	08/91	Possin et al.			
	AK	6,143,662	11/00	Rhodes et al.			
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